

# Reliability-Aware Dynamic Energy Management in Dependable Embedded Real-Time Systems

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Recent studies show that, voltage scaling, which is an efficient energy management technique, has a direct and negative effect on system reliability because of the increased rate of transient faults (e.g., those induced by cosmic particles). In this work, we propose energy management schemes that explicitly take system reliability into consideration. The proposed *reliability-aware* energy management schemes *dynamically* schedule recoveries for tasks to be scaled down to recuperate the reliability loss due to energy management. Based on the amount of available slack, the application size and the fault rate changes, we analyze when it is profitable to reclaim the slack for energy savings without sacrificing system reliability. Checkpoint technique is further explored to efficiently use the slack. Analytical and simulation results show that, the proposed schemes can achieve comparable energy savings as *ordinary* energy management schemes (which are reliability-ignorant) while preserving system reliability. The ordinary energy management schemes that ignore the effects of voltage scaling on fault rate changes could lead to drastically decreased system reliability.

Categories and Subject Descriptors: C.3 [**Special-purpose and application-based systems**]: Real-time and embedded systems; C.4 [**Performance of Systems**]: Fault tolerance, performance attributes; D.4.5 [**Operating Systems**]: Reliability—*Checkpoint/restart*

General Terms: Systems, Algorithms, Management

Additional Key Words and Phrases: Power management, dynamic voltage scaling

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## 1. INTRODUCTION

The performance of modern computing systems has increased at the expense of dramatically increased power consumption. The increased power consumption reduces the operation time for battery-operated embedded systems (e.g., PDAs and cell phones) as well as increases the operation cost for high performance parallel systems (e.g., data centers and server farms), where the excessive amount of heat generated requires high cooling capacity. Many hardware and software techniques have been proposed to manage power consumption in modern computing systems and power aware computing has become an important research area recently. As an efficient energy management technique, *voltage scaling*, which reduces system supply voltage for lower operation frequencies [Weiser et al. 1994; Yao et al. 1995],

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Parts of this work appeared in IEEE RTAS'06.

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has been used extensively in the recently proposed power management schemes [Aydin et al. 2001; Mossé et al. 2000; Pillai and Shin 2001; Saewong and Rajkumar 2003].

Another traditionally important avenue in real-time systems research is fault tolerance. For safety-critical real-time systems, where the consequence of a failure can be catastrophic, faults must be detected, and appropriate recovery operations must be completed before the deadline. It has been reported that *transient* faults occur much more frequently than *permanent* faults [Castillo et al. 1982; Iyer and Rossetti 1984; Iyer et al. 1986]. Moreover, with continuing scaling of CMOS technologies and adjustment of design margins for higher performance, it is expected that, in addition to the systems that traditionally operate in electronics-hostile environments (such as those in outer space), practically all digital systems will be much more vulnerable to the transient faults [Ernst et al. 2004; Wang et al. 2004]. In this work, we will focus on transient faults and explore the *backward error recovery* techniques, which restore the system state to a previous safe state and repeat the computation [Pradhan 1986], to tolerate them.

However, both voltage scaling and backward recovery techniques rely on the active use of system slack. When more slack time is dedicated as temporal redundancy for backward recovery to increase system reliability, less slack is available for energy management to save energy. Therefore, there is an interesting trade-off between system reliability and energy consumption [Zhu et al. 2004]. Moreover, it has been shown that voltage scaling has a direct effect on the rate increases of transient faults, especially for those induced by cosmic ray radiations, which further complicates the interplay between system reliability and energy efficiency.

Due to the effects of cosmic ray radiations, soft errors (i.e., transient faults) can be caused by the atmospheric nuclear/high energy particles (alpha-particles, protons and neutrons) when they strike the sensitive region in a semiconductor device. In general, the error rate is exponentially related to the *critical charge* (which is the smallest charge required to cause a soft error in a circuit node) of a circuit [Hazucha and Svensson 2000]. Since the critical charge is proportional to system supply voltage [Seifert et al. 2001], when system supply voltage is reduced, the critical charge decreases and low energy cosmic particles could cause an error. Considering the number of particles with lower energy is much more than that of particles with higher energy in the cosmic rays [Ziegler 1998], scaling down voltages and frequencies for energy savings could lead to dramatically increased transient fault rates [Zhu et al. 2004]. Therefore, voltage scaling has a severe effect on system reliability [Ernst et al. 2004; Shivakumar et al. 2002; Zhu et al. 2004] and should be carefully evaluated before it is applied, especially for safety-critical embedded real-time applications, such as satellite and surveillance systems, where both high level of reliability and low energy consumption are important.

Traditionally, to achieve a certain level of system reliability in the worst case, only static slack in a system has been explored as temporal redundancy. However, as real-time applications exhibit large variations in actual execution time, and in many cases, only consume a small fraction of their worst case execution time [Ernst and Ye 1997], large amount of dynamic slack is available during run-time. As mentioned earlier, simply reclaiming this dynamic slack for energy savings through

voltage scaling technique could dramatically reduce system reliability due to increased failure rates as well as extended execution time [Ernst et al. 2004; Zhu et al. 2004]. Therefore, for dependable embedded real-time systems (such as the ones deployed in out-space explorers), where both high system reliability and low energy consumption are equally important, special considerations are needed when exploiting dynamic slack for energy savings.

Though fault tolerance through redundancy and energy management through voltage and frequency scaling have been well studied in the context of real-time systems independently, there are relatively less research addressing the combination of fault tolerance and energy management [Ejlali et al. 2005; Elnozahy et al. 2002; Melhem et al. 2004; Rashid et al. 2005; Unsal et al. 2002; Zhang and Chakrabarty 2004]. In this work, we propose schemes that utilize dynamic slack for energy savings while taking system reliability into consideration. Specifically, the proposed *reliability-aware* energy management schemes *dynamically* schedule recoveries for tasks to be scaled down using dynamic slack to recuperate the reliability loss due to energy management. To the best of our knowledge, this is the first work that addresses the complications of exploring dynamic slack for both energy and reliability. The main contributions of this paper are three-fold:

- First, we propose a reliability-aware dynamic energy management scheme that can achieve significant energy savings without degrading system reliability.
- Second, depending on the amount of available slack and the size of the application, we identify the situation when it is profitable to reclaim dynamic slack for energy savings without sacrificing system reliability.
- Third, checkpointing techniques are further explored for the reliability-aware dynamic energy management scheme to efficiently use dynamic slack.

Analytical and simulation results show that ignoring the effects of voltage scaling on fault rates changes could lead to drastically decreased system reliability and the proposed schemes can achieve comparable energy savings as ordinary energy management schemes while preserving system reliability.

The remainder of this paper is organized as follows. The models and problem description are presented in Section 2. Reliability-aware dynamic energy management is proposed and analyzed in Section 3 and Section 4 further explores checkpointing techniques to efficiently use dynamic slack. The simulation results are presented and discussed in Section 5. Section 6 addresses the closely related work and Section 7 concludes the paper.

## 2. MODELS AND PROBLEM DESCRIPTION

### 2.1 Power Model

For embedded systems, the power is consumed mainly by the processor, memory, I/O interfaces and underlying circuits. While the power consumption is dominated by dynamic power dissipation, which is quadratically related to supply voltage and linearly related to frequency [Burd and Brodersen 1995], the static leakage power is ever-increasing and cannot be ignored, especially with the scaled feature size and increased levels of integration [Jejurikar et al. 2004; Sinha and Chandrakasan 2001]. To incorporate all the power consuming components in an embedded system while

keeping the power model simple, the power consumption in a system is divided into two major components: *static power* and *active power* [Zhu et al. 2004].

The static power, which may be removed only by powering off the whole system, includes (but not limited to) the power to maintain basic circuits, keep the clock running and the memory in power saving sleep modes [Lebeck et al. 2000]. The active power is further divided into two parts: *frequency-independent* active power and *frequency-dependent* active power. Frequency-independent active power consists of part of memory and processor power as well as any power that can be efficiently removed by putting systems into sleep state(s) and is independent of system supply voltages and processing frequencies [Intel-Corp. 2001; Lebeck et al. 2000]. Frequency-dependent active power includes processor's dynamic power and any power that depends on system supply voltages and processing frequencies [Burd and Brodersen 1995; Sinha and Chandrakasan 2001]. Considering the almost linear relation between supply voltage and operating frequency [Burd and Brodersen 1995], *voltage scaling* reduces the supply voltage for lower frequencies [Pering et al. 1998]. In this paper, we use frequency changes to stand for changing both supply voltage and frequency and adopt the power model developed in [Zhu et al. 2004]:

$$P = P_s + \hbar(P_{ind} + P_d) = P_s + \hbar(P_{ind} + C_{ef}f^m) \quad (1)$$

where  $P_s$  is the static power,  $P_{ind}$  is the frequency-independent active power and  $P_d$  is the frequency-dependent active power. Both  $P_s$  and  $P_{ind}$  are system dependent *constants*.  $\hbar = 1$  if the system is *active* (defined as having computation in progress); otherwise (i.e., the system is in sleep mode or turned off)  $\hbar = 0$ . The effective switching capacitance  $C_{ef}$  and the dynamic power exponent  $m$  (in general, larger than or equal to 2) are system/application dependent constants [Burd and Brodersen 1995] and  $f$  is the processing frequency. For easy discussion, normalized frequencies are used and the maximum frequency  $f_{max}$  is assumed to be 1 (with corresponding normalized supply voltage  $V_{max} = 1$ ). The maximum frequency-dependent active power is denoted by  $P_d^{max}$  and we assume  $P_s = \alpha P_d^{max}$  and  $P_{ind} = \beta P_d^{max}$ .

From Equation (1), intuitively, lower frequencies result in less frequency-dependent active energy consumption. But with reduced speed, the application will run longer and thus consume more static energy and frequency-independent active energy. Hence, in general, an *energy-efficient frequency, below which voltage scaling starts to consume more total energy*, does exist<sup>1</sup>. In real-time applications, the time and energy overhead of turning on/off a device that is actively used by the application may be prohibitive [Bohrer et al. 2002]. For the time interval considered (e.g., within application's deadline), we assume that the working system is always on (but several components may be put to low-power sleep states for energy savings) and  $P_s$  is always consumed. Consequently, the total energy consumption of a *running* application at frequency  $f$  can be modeled as:

$$E = P_s \cdot D + (P_{ind} + C_{ef}f^m) \cdot \frac{c}{f} \quad (2)$$

<sup>1</sup>We note that this conclusion has been also reached by several research groups, though through different energy modeling techniques [Elnozahy et al. 2002; Fan et al. 2003; Jejurikar et al. 2004; Irani et al. 2003; Saewong and Rajkumar 2003].

where  $D$  is the operation interval,  $c$  is the worst case execution time of the application at the maximum frequency  $f_{max}$  and  $\frac{c}{f}$  is the execution time of the application at frequency  $f$ . That is, although  $P_s$  affects the *total* energy consumption, the amount of *energy savings* from voltage scaling is *independent* of it. For easy discussion, in what follows, we assume  $P_s = 0$  and focus on active power<sup>2</sup>.

From Equation 2, it is easy to find out that the *energy efficient frequency* is [Zhu et al. 2004]:

$$f_{ee} = \sqrt[m]{\frac{\beta}{m-1}} \quad (3)$$

For energy consideration, we should never run at a frequency below  $f_{ee}$ , since doing so consumes more energy. For simplicity, we assume that  $f_{ee} \geq f_{low}$ , where  $f_{low}$  is the lowest frequency in the system, and define the *minimum energy efficient frequency* as  $f_{min} = \max\{f_{low}, f_{ee}\} = f_{ee}$ . Moreover, frequency is assumed to be able to change continuously from  $f_{max}$  to  $f_{min}$ . For voltage scaling capable modern processors that have only a few discrete frequency/voltage levels [Intel-Corp. 2001], after reclaiming the slack and obtaining the desired frequency, running the task at the next higher discrete frequency level will always ensure to meet the task's timing constraints. Moreover, one can also use two adjacent discrete speed levels to emulate the execution at any frequency [Ishihara and Yauura 1998].

## 2.2 Fault Model

During the execution of an application, a fault may occur due to various reasons, such as hardware failures, software errors and the effects of cosmic ray radiations. Since *transient* faults occur much more frequently than *permanent* faults [Castillo et al. 1982; Iyer and Rossetti 1984; Iyer et al. 1986], in this paper, we focus on transient faults, especially the ones caused by cosmic ray radiations, and explore *backward recovery* techniques to tolerate them. It is assumed that faults are detected using *sanity* or *consistency* checks [Pradhan 1986]. Should an error be detected, the system's state is restored to a previous safe state and the computation is repeated.

Transient faults that are caused by radiations in semiconductor circuits have been known and well studied since the late 1970s [Ziegler 1998]. However, considering the various factors that affect the transient fault rate (such as cosmic ray flux, technology feature size, chip capacity, supply voltage and operating frequency), obtaining a *precise and formal model* is an extremely challenging task [Semiconductor 2004; Shivakumar et al. 2002; Ziegler 2004]. In general, transient fault rate, also known as *soft error rate (SER)*, which is exponentially-related to the *critical charge* ( $Q_{crit}$ ), of a circuit is given by the following equation [Hazucha and Svensson 2000]:

$$SER \propto F \times A \times e^{-\frac{Q_{crit}}{Q_s}} \quad (4)$$

where  $Q_{crit}$  is the smallest charge needed to cause a soft error;  $A$  and  $Q_s$  are circuit-related constants; and  $F$  is the neutron flux (i.e., radiation intensity). Moreover, the critical charge is proportional to system supply voltage [Seifert et al. 2001]. When the system supply voltage is reduced, the critical charge decreases, which will

<sup>2</sup>For systems with multiple processing units, some processing units may be powered off for energy efficiency and the energy savings will be affected by  $P_s$  [Xu et al. 2005; Zhu et al. 2005].

increase the transient fault rate. For example, increased SERs have been observed with lower supply voltages for both memory [Ziegler 2004] and processors [Seifert et al. 2001].

Based on these observations, we have studied the effects of low power techniques on transient fault rates [Zhu et al. 2004]. Assuming that radiation-induced transient faults follow a Poisson distribution with an average fault rate  $\lambda$  [Zhang and Chakrabarty 2003], for systems running at frequency  $f$  ( $f \leq f_{max}$ , and corresponding supply voltage  $V$ ), the function giving the average transient fault rate is generally expressed as [Zhu et al. 2004]:

$$\lambda(f) = \lambda_0 g(f) \quad (5)$$

where  $\lambda_0$  is the average fault rate corresponding to the maximum frequency  $f_{max} = 1$  (and supply voltage  $V_{max}$ ). That is  $g(f_{max}) = 1$ .

When supply voltage is scaled down, with smaller critical charges, lower energy particles could cause an error with a *higher* probability [Ziegler 1998]. Considering the exponential term in Equation (4), and the fact that the number of low-energy particles is two magnitude higher than that of the high-energy particles [Ziegler 1998], a more *specific* fault rate model for voltage scaling has been suggested in our previous study [Zhu et al. 2004]:

$$\lambda(f) = \lambda_0 g(f) = \lambda_0 10^{\frac{d(1-f)}{1-f_{min}}} \quad (6)$$

where  $d$  ( $> 0$ ) is a constant. The maximum average fault rate is assumed to be  $\lambda_{max} = \lambda_0 10^d$ , which corresponds to the lowest frequency  $f_{min}$  (and supply voltage  $V_{min}$ ). That is, reducing the supply voltage and frequency for energy savings results in *exponentially* increased fault rates and larger  $d$  indicates that the fault rate is more sensitive to voltage scaling. Although the exponential fault rate model is used in the analysis and simulations, the reliability-aware energy management schemes proposed in this paper are very generic and do not rely on any specific fault model.

### 2.3 Problem Description

In this work, we consider a real-time application that consists of a set of *aperiodic* tasks that share a common deadline  $D$ . Note that, for periodic applications,  $D$  can also represent the *period*. The worst case execution time (WCET) of task  $T_i$  at the maximum frequency  $f_{max}$  is assumed to be  $c_i$  ( $i = 1, \dots, n$ ). When all tasks use their WCETs at the maximum frequency  $f_{max}$ , it is assumed that all tasks can finish their execution within the deadline  $D$  and the task set is schedulable. Moreover, considering that the reliability of a real-time system depends on the correct execution of *all* tasks in an application, without loss of generality, the application reliability,  $R_0 = \prod_{i=1}^n R_i^0$ , is assumed to be *satisfactory*. Here,  $R_i^0 = e^{-\lambda_0 c_i}$  is the probability of task  $T_i$  being executed correctly (from the Poisson fault arrival pattern and the average fault rate  $\lambda_0$ ). That is, no recovery tasks are *statically* scheduled to achieve the required reliability<sup>3</sup>  $R_0$ , which will be preserved at run-time.

<sup>3</sup>When recovery tasks are *statically* scheduled to satisfy higher levels of reliability requirements, our proposed schemes will treat such recovery tasks as normal tasks and preserve the higher levels of reliability that should be achieved.

Due to early completion of tasks at run time, dynamic slack will exist during the execution of tasks [Ernst and Ye 1997]. **For a given amount of available slack  $S$ , we focus on the problem of how to use  $S$  for energy savings without sacrificing system reliability, while taking the effects of voltage scaling on fault rates into consideration.**

In order to preserve the reliability,  $R_0$ , of an application, for simplicity, we focus on maintaining the reliability of *individual* tasks in this work. That is, we propose schemes to keep the probability of task  $T_i$  being correctly executed no less than  $R_i^0$  ( $i = 1, \dots, n$ ). Recoveries of tasks will be scheduled *dynamically* if needed. The overall performance of the proposed schemes for the whole application will be evaluated through simulations in Section 5.

When errors are detected at a task's completion, the task may be *re-executed* to recover from transient faults. In the next Section, we first consider the case where the amount of available slack  $S$  is no less than  $c_k$ , the size of the next task  $T_k$ , and propose a *reliability-aware* dynamic energy management scheme which *dynamically* schedules a recovery task (i.e., a simple re-execution) for  $T_k$  to recuperate the reliability loss due to energy management. Section 4 further explores checkpointing techniques to efficiently use the available slack, especially for the cases where  $S$  is smaller than  $c_k$ .

### 3. RELIABILITY-AWARE DYNAMIC ENERGY MANAGEMENT

Although sophisticated dynamic power management schemes that explore tasks' statistical information have been proposed [Aydin et al. 2001; Mossé et al. 2000], we will focus on the *greedy* scheme for its simplicity. Exploring other advanced schemes is beyond the scope of this paper and will be considered in our future work. We first illustrate the problem of the *ordinary* greedy power management on reliability in Section 3.1. Then Section 3.2 presents the new reliability-aware greedy energy management scheme and the analysis.

#### 3.1 Ordinary Greedy Power Management

In *ordinary greedy* power management, all the available dynamic slack will be used to scale down the processing of the next task for energy savings provided that such allocation complies with task's timing constraints [Aydin et al. 2001; Mossé et al. 2000] and/or the minimum energy-efficient frequency limitation [Zhu et al. 2004]. For example, as shown in Figure 1a, due to the early completion of previous tasks, there are 3 units of available dynamic slack at time  $t$ , that is,  $S = 3$ . The WCET of the next ready task  $T_k$  is  $c_k = 2$ . In the figures, the X-axis represents time, the Y-axis represents processing frequency (e.g., cycles per time unit), and the area of the task box defines the workload (e.g., number of cycles) of the task. Recall that  $D_k$  is the deadline of task  $T_k$ .

Suppose that  $\beta = 0.1$  (i.e.,  $P_{ind} = 0.1P_d^{max}$ ) and  $m = 3$ , we have the minimum energy efficient frequency  $f_{ee} = 0.37$  (recall that  $f_{max} = 1$ , Section 2) [Zhu et al. 2004]. Therefore, all the available dynamic slack  $S$  can be allocated to task  $T_k$  and the processing speed of  $T_k$  can be reduced from  $f_{max} = 1$  to  $f = \frac{2}{2+3} = 0.4$  as shown in Figure 1b. From Equation 1, it is easy to find that scaling down the processing of  $T_k$  could save 63% of the *active energy*.

However, as discussed in Section 2, with reduced processing frequency and supply

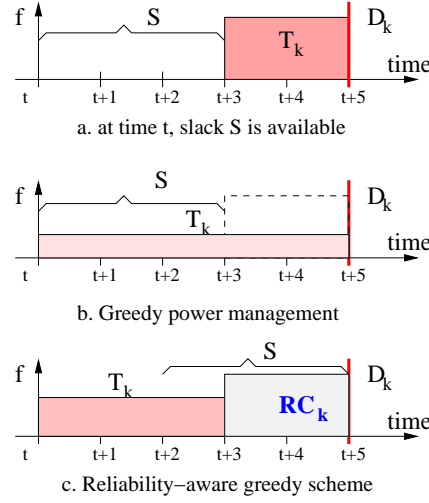


Fig. 1. Ordinary and Reliability-Aware Greedy Schemes.

voltage, the processing of task  $T_k$  is more susceptible to transient faults [Ernst et al. 2004; Zhu et al. 2004]. Suppose that the exponent in the fault rate model is  $d = 2$  (see Equation 6 in Section 2), the probability of having fault(s) during the execution of task  $T_k$  at the reduced speed will be:

$$\begin{aligned}
 \rho_k &= 1 - R_k = 1 - e^{-\lambda_0 10^{\frac{d(1-f)}{1-f_{min}}}(S+c_k)} \\
 &= 1 - e^{-\lambda_0 10^{\frac{d(1-f)}{1-f_{min}} \frac{c_k}{f}}} = 1 - e^{-\lambda_0 c_k 10^{\frac{2(1-0.4)}{1-0.37} \frac{1}{0.4}}} \\
 &\approx 1 - (R_k^0)^{200} = 1 - (1 - \rho_k^0)^{200} \approx 200\rho_k^0
 \end{aligned} \tag{7}$$

where  $\rho_k^0$  is the probability<sup>4</sup> of having fault(s) when task  $T_k$  uses its WCET at the maximum processing frequency  $f_{max}$ . That is, though 63% active energy is saved by scaling down the processing of task  $T_k$ , it leads to approximately 200 times higher in the probability of failure! The increase in the probability of failure during the processing of individual tasks will degrade the overall system reliability, which is unbearable, especially for safety-critical systems where the requirement for high levels of reliability is strict.

### 3.2 Reliability-Aware Greedy Scheme

In addition to being used by energy management schemes for energy savings, slack time can also be used as temporal redundancy to increase system reliability. To recuperate the reliability loss due to energy management, we can reserve some slack as temporal redundancy for scheduling recoveries/backups for tasks to be scaled down. For simplicity, here we assume that the recovery is in the form of *re-execution* and it has the same size of the task to be recovered [Pradhan 1986].

The *reliability-aware greedy (RA-Greedy)* power management scheme will dynamically schedule a *recovery* for the task to be scaled before applying slack reclamation

<sup>4</sup>Note that,  $\rho_k^0$  is a small number (usually  $< 10^{-4}$ ).



for energy savings. The recovery will be executed (if needed) at the maximum frequency  $f_{max} = 1$ . Notice that, in this section, the amount of dynamic slack  $S$  is assumed to be no less than  $c_k$ , the size of next task  $T_k$ . After reserving  $c_k$  units of dynamic slack for the recovery task, the remaining dynamic slack ( $S - c_k$ , if any) can be used to scale down the execution of  $T_k$  for energy savings. For example, as shown in Figure 1c, a recovery task  $RC_k$  is scheduled for task  $T_k$  which uses 2 units of dynamic slack. The remaining 1 unit of dynamic slack allows task  $T_k$  to run at a lower frequency  $f_k = \frac{2}{2+1} = 0.66$  and save energy.

**3.2.1 System Reliability under RA-Greedy.** With the additional recovery task  $RC_k$ , the reliability  $R_k$  of task  $T_k$  will be the summation of the probability of primary task  $T_k$  being executed correctly and the probability of having fault(s) during  $T_k$ 's execution while  $RC_k$  being executed correctly. Notice that, if the execution of the primary task  $T_k$  is faulty, the recovery task  $RC_k$  will be executed at the maximum frequency  $f_{max}$  and the probability of its *fault-free* execution is  $e^{-\lambda_0 c_k} = R_k^0$ . Therefore, we have:

$$R_k = e^{-\lambda(f_k)S} + \left(1 - e^{-\lambda(f_k)S}\right) R_k^0 > R_k^0 \quad (8)$$

where  $\lambda(f_k)$  is the fault rate at the reduced frequency  $f_k$ . From the above equation, we can see that, under the RA-Greedy scheme, with the help of the additional recovery task  $RC_k$ , the reliability of task  $T_k$  is *always* better than  $R_k^0$  regardless different fault rate increases (i.e., different values of  $d$  in Equation 6) and the reduced processing frequency  $f_k$  of the primary task  $T_k$ . That is, **when the amount of dynamic slack is no less than the size of the next task, by dynamically scheduling a recovery task before applying energy management, the RA-Greedy scheme can guarantee to achieve better reliability for individual tasks, and thus preserve system reliability.**

**3.2.2 Expected Energy Consumption under RA-Greedy.** Recall that we assume  $P_s = 0$  and focus on active power in this paper. Suppose that the energy consumption to execute task  $T_k$  for time  $c_k$  at the maximum frequency  $f_{max}$  is  $E_k^0 = (P_s + P_{ind} + P_d^{max})c_k = (P_{ind} + P_d^{max})c_k = (\beta + 1)P_d^{max}c_k$ . Considering the probability of  $RC_k$  being executed, the *expected energy consumption* for processing task  $T_k$  will be:

$$\begin{aligned} E_k &= (P_{ind} + C_{ef}f_k^m)S + (1 - e^{-\lambda(f_k)S}) \cdot E_k^0 \\ &= E_k^0 \left[ 1 - e^{-\lambda(f_k)S} + \frac{(\beta + \frac{c_k^m}{S^m})S}{1 + \beta} \right] \end{aligned} \quad (9)$$

Intuitively, the more the available dynamic slack is allocated for energy management, the lower the processing frequency can be for executing task  $T_k$ , and thus more energy savings can be obtained. However, due to the limitation of the minimum energy efficient frequency  $f_{ee}$ , the maximum amount of dynamic slack that should be allocated to task  $T_k$  for energy management is limited, which can be easily calculated as  $\frac{c_k}{f_{ee}} - c_k$ . Consider the amount of slack reserved for recovery is  $c_k$ , the maximum amount of *usable* dynamic slack that may be applied when processing  $T_k$  will be  $US_{max} = (\frac{c_k}{f_{ee}} - c_k) + c_k = \frac{c_k}{f_{ee}}$ . When more dynamic slack

than  $US_{max}$  is available, part of the slack will be saved for future tasks due to energy consideration.

Moreover, with reduced processing frequency and supply voltage, the fault rate increases and the execution of  $T_k$  takes more time, which results in higher probability of having fault(s) during the execution of  $T_k$ . Therefore the probability of recovery task  $RC_k$  being executed increases, which may *overshadow* the energy savings and lead to more expected energy consumption. However, considering the exponential component in Equation 9, it is hard to obtain a simple close formula for the optimal amount of dynamic slack that minimizes the expected energy consumption. In what follows, we present some analytical results to illustrate the relation between the expected energy consumption, the amount of available dynamic slack and the fault rate changes due to energy management.

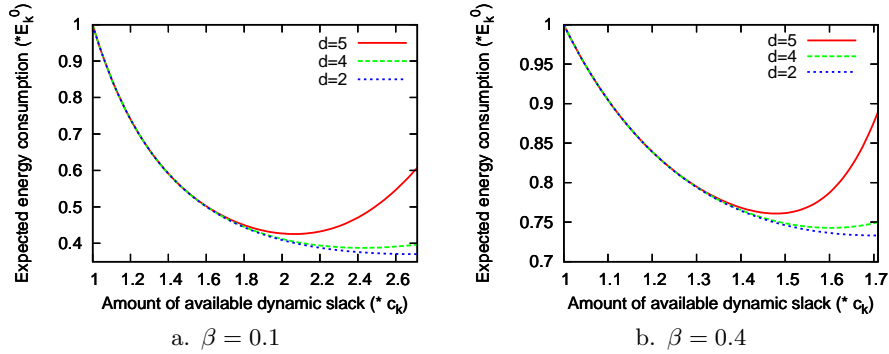


Fig. 2. The normalized expected energy consumption vs. the amount of available dynamic slack for different frequency-independent power (i.e.,  $\beta = 0.1$  and  $0.4$ ).

Without loss of generality, in the analysis, we assume  $c_k = 1$  and  $\lambda_0 = 10^{-6}$  (which corresponds to 100,000 FITs, *failure in time* in terms of errors per billion hours of use per megabit, that is a reasonable fault rate as reported [Semiconductor 2004; Ziegler 2004]). Moreover, we assume  $\alpha = 0$  (i.e.,  $P_s = 0$ ) and  $m = 3$ . Figure 2 shows the expected energy consumption for executing task  $T_k$ , normalized to  $E_k^0$ , versus the amount of available dynamic slack under different frequency-independent power ( $\beta$ ) and fault rate changes ( $d$ ). Notice that, one unit ( $c_k$ ) of dynamic slack is reserved for the recovery task and the minimum amount of dynamic slack considered is  $c_k$ . From Section 2, for different frequency-independent power  $\beta = 0.1$  and  $0.4$ , the corresponding energy efficient frequencies are  $f_{ee} = 0.37$  and  $0.58$ , which in turn limits the maximum amount of dynamic slack used by RA-Greedy scheme  $US_{max} = \frac{c_k}{f_{ee}}$  to be  $2.70c_k$  and  $1.72c_k$ , respectively (see the X-axis in the figure).

From the figures we can see that, for the different fault rate increases considered (i.e.,  $d = 2, 4$  and  $5$ ), when the amount of available dynamic slack is more than  $c_k$  ( $= 1$ ), the size of the next task  $T_k$ , dynamic slack is available for energy management. The expected energy consumption to execute  $T_k$  is less than  $E_k^0$  and up to 60% of energy savings is expected when  $\beta = 0.1$  and  $d \leq 4$ . As the amount of available dynamic slack increases, more slack is available for energy management

and the expected energy consumption for executing task  $T_k$  generally decreases. However, when the fault rate increases dramatically with reduced processing frequencies and supply voltages (e.g.,  $d = 5$ ), as more dynamic slack is available and the reduced frequency approaches  $f_{ee}$ , more expected energy may be consumed due to the increased probability of recovery task being executed. In this case, the optimal amount of dynamic slack to minimize expected energy consumption is less than  $US_{max}$ .

Notice that, when the fault rate increase is not that severe (e.g.,  $d \leq 4$ ), the maximum amount of usable dynamic slack  $US_{max}$  limited by  $f_{ee}$  is very close to the optimal amount of slack that minimizes the expected energy consumption. Considering the difficulty of finding the close formula for the optimal amount of slack, for the simulations in Section 5, the amount of dynamic slack that will be allocated for energy management is only limited by  $f_{ee}$  (i.e., up to  $US_{max} - c_k$  amount of dynamic slack will be used for energy management). Moreover, for higher frequency-dependent active power (i.e.,  $\beta = 0.4$ ),  $f_{ee}$  increases and  $US_{max}$  decreases, which results in less energy savings (note the difference in the scale of Y-axis in Figure 2).

We have shown that the RA-Greedy scheme can achieve significant energy savings while guaranteeing to preserve system reliability regardless the negative effects of voltage scaling on transient fault rates. However, the amount of slack needed by the RA-Greedy scheme may be considerable, especially for large tasks. To utilize the slack more efficiently, instead of scheduling a whole recovery task, checkpoints may be employed to re-compute only the faulty section for more energy savings as well as better system reliability [Krishma and Singh 1993; Lee et al. 1999; Melhem et al. 2004].

#### 4. CHECKPOINTING FOR BETTER PERFORMANCE

Checkpointing techniques insert checkpoints during the execution of a task. Within a checkpoint, the state of a system is checked and correct states are saved to a stable storage [Pradhan 1986]. When faults are detected, the execution is rolled back to the latest correct checkpoint and re-compute the faulty section by exploring the temporal redundancy [Krishma and Singh 1993; Lee et al. 1999]. Checkpoints can be *uniformly* or *non-uniformly* distributed among an application [Melhem et al. 2004]. In this work, we consider uniformly distributed checkpoints only.

For example, Figure 3a shows that there are 2 units of dynamic slack available at time  $t$ , which is less than  $c_k = 3$ , the size of the next ready task  $T_k$ . Apparently, the RA-Greedy scheme could not use this slack and it may be wasted (e.g., if  $T_k$  is the last task). If the overhead of employing one checkpoint is  $r = 0.125$  and 3 checkpoints are inserted, Figure 3b illustrates the case of one recovery section being scheduled. Here there is 0.5 units of remaining dynamic slack, which can be used to scale down the processing of the *primary* task sections for energy savings as shown in Figure 3c.

The more the checkpoints are, the smaller a task section is. Thus, less slack is needed for recoveries. However, checkpoints also take time and consume energy. Therefore, there is a tradeoff regarding the number of checkpoints that should be employed to minimize the response time [Krishma and Singh 1993] or energy

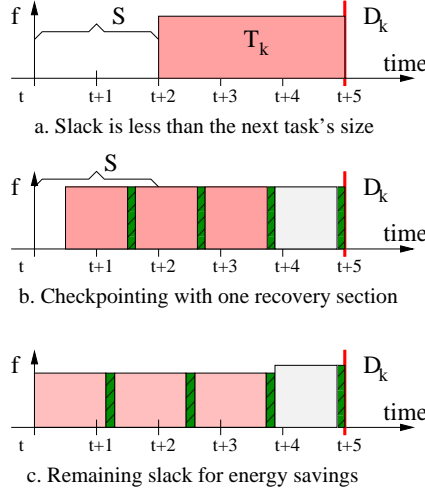


Fig. 3. Reliability-Aware Energy Management with Checkpoints.

consumption [Melhem et al. 2004]. For simplicity, we focus on the optimal number of checkpoints that minimize the recovery overhead and explore the efficient usage of the slack to save energy while preserving system reliability. That is, **for given amount of available slack  $S$  and the next task  $T_k$ , we study the relation between the checkpoint overhead, the amount of energy savings and the number of recovery sections needed to preserve system reliability.**

#### 4.1 Checkpoints with Single Recovery Section

To compensate the reliability loss due to energy management and checkpoint overhead, *at least* one recovery section is needed. In this Section, we consider first the simple case that only has a single recovery section and analyze its performance on system reliability. When one recovery is not enough to recuperate the reliability loss, the analysis is further generalized to multiple recovery sections in Section 4.2.

For easy discussion, we assume that the overhead of taking one checkpoint is  $r = \gamma \cdot c_k$ , where  $c_k$  is the WCET of the next task  $T_k$ . If  $n$  checkpoints are inserted during the execution of  $T_k$ , the size of one recovery section will be  $\frac{c_k}{n}$  and we have:

$$S \geq n \cdot r + \left(r + \frac{c_k}{n}\right) = \left(n\gamma + \gamma + \frac{1}{n}\right)c_k \quad (10)$$

In order for  $n$  to have a real (non-imaginary) solution, we can easily find that the minimum amount of slack needed due to timing constraints is  $S_{min}^{time} = (\gamma + 2\sqrt{\gamma})c_k$  with the optimal number of checkpoints being  $n_{opt} = \left\lfloor \sqrt{\frac{1}{\gamma}} \right\rfloor$  or  $n_{opt} = \left\lceil \sqrt{\frac{1}{\gamma}} \right\rceil$ . However, considering the integer property of  $n_{opt}$  and the energy overhead incurred by checkpoints, the minimum amount of slack needed for energy savings  $S_{min}^{energy}$  should be larger than  $S_{min}^{time}$  as illustrated in Section 4.2.2.

With the optimal number of checkpoints  $n_{opt}$  and one recovery section, the amount of available slack for energy management will be  $S - (n_{opt} + 1)r - \frac{c_k}{n_{opt}}$ , which can be used to scale down the execution of the primary sections. Therefore,

the reduced frequency to execute the primary sections will be

$$f_{ckpt} = \frac{c_k + n_{opt} \cdot r}{S + c_k - r - \frac{c_k}{n_{opt}}} \quad (11)$$

and each primary section will take  $t_{primary} = \frac{S + c_k - r - \frac{c_k}{n_{opt}}}{n_{opt}}$  time units. From

Section 2, the fault rate at frequency  $f_{ckpt}$  will be  $\lambda(f_{ckpt}) = \lambda_0 10^{\frac{d(1-f_{ckpt})}{1-f_{min}}}$  and the probability of having fault(s) during the execution of one primary section is  $\rho_{primary} = 1 - e^{-\lambda(f_{ckpt})t_{primary}}$ . Notice that, the recovery section is executed at  $f_{max}$  and the probability of having fault(s) during the execution of the recovery section is  $\rho_{recovery} = 1 - e^{-\lambda_0(r + \frac{c_k}{n_{opt}})}$ . Therefore, the reliability of executing task  $T_k$  is

$$R_k^{ckpt} = (1 - \rho_{primary})^{n_{opt}} + n_{opt} \cdot \rho_{primary} (1 - \rho_{primary})^{n_{opt}-1} (1 - \rho_{recovery}) \quad (12)$$

where the first part is the probability of all primary sections being executed correctly and the second part is the probability of having fault(s) during the execution of *exactly one* primary section while the recovery section being executed correctly.

From Equation 12,  $R_k^{ckpt}$  is determined by the amount of available dynamic slack  $S$ , checkpoint overhead  $r$  and fault rate changes  $d$ . For a given checkpoint overhead, more dynamic slack leads to lower reduced frequency for the primary sections, which in turn leads to higher probability of failure and lower reliability  $R_k^{ckpt}$ . However, due to the complexity of Equation 12, it is hard to find the close formula for  $S$  to ensure  $R_k^{ckpt} \geq R_k^0$  and we illustrate the relation between  $S$  and  $R_k^{ckpt}$  in the following analysis.

Figure 4 shows the normalized probability of failure,  $\frac{1 - R_k^{ckpt}}{1 - R_k^0}$ , when executing task  $T_k$  with different amount of available dynamic slack under different checkpoint overheads. Here, we limit the analysis to the case of  $S < c_k$  since the RA-Greedy scheme can guarantee system reliability when  $S > c_k$ . The same as before, we assume  $m = 3$ ,  $\lambda_0 = 10^{-6}$  and  $c_k = 1$ . Moreover,  $\beta$  is assumed to be 0.1 and we have  $f_{ee} = 0.37$ . Therefore, for a given checkpoint overhead  $r = \gamma c_k$ , the amount of dynamic slack considered will be in the range of  $S_{min}^{time}$  ( $= \gamma + 2\sqrt{\gamma}$ ) and 1.

From the figure, we can see that, with one recovery section, the normalized probability of failure to execute task  $T_k$  is lower than 1 most of the time. The exception comes from the case where the checkpoint overhead is low (i.e.,  $\gamma = 0.01$ ; see Figure 4a) which leaves more slack for energy management and the reduced frequency is close to  $f_{ee}$ . With the exponent of fault rate model being  $d = 5$ , the fault rate at  $f_{ee}$  is  $10^5$  time higher than  $\lambda_0 = 10^{-6}$  and leads to worse than  $R_k^0$  reliability. However, with moderate fault rate increase (e.g.,  $d \leq 4$ ), for the cases we considered, checkpoints with one recovery section could obtain higher reliability when executing task  $T_k$ .

Moreover, the faster the fault rate increases (i.e., larger values of  $d$ ) with reduced frequencies and supply voltages, the higher the probability of failure and the lower the reliability. Assuming constant fault rate (e.g.,  $d = 0$ ) is too optimistic and could lead to lower reliability than expected when exploring slack for energy management, which is the same observation as our previous results [Zhu et al. 2004].

From the above analysis, we can see that checkpointing with single recovery

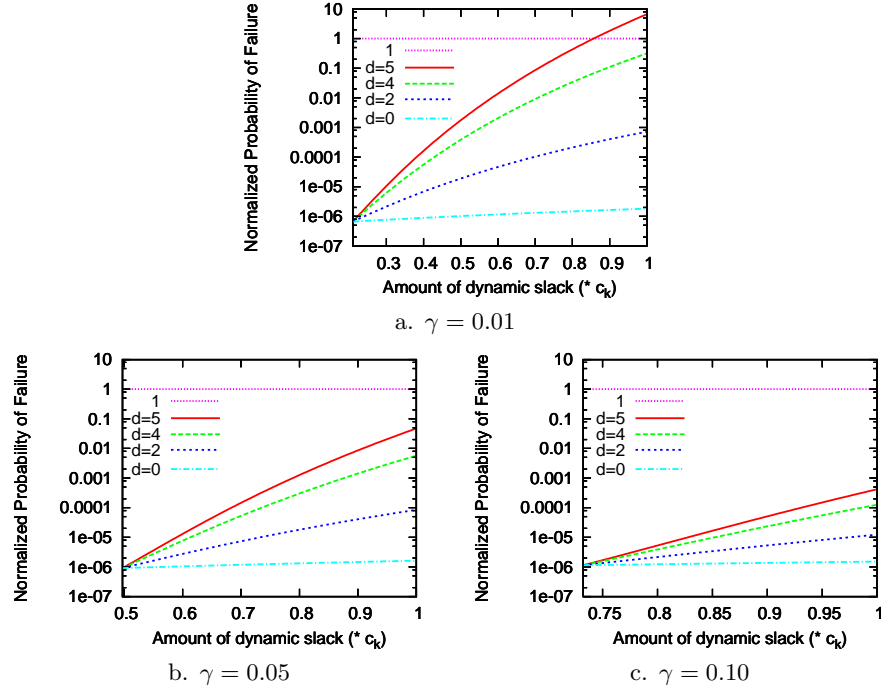


Fig. 4. The normalized probability of failure vs. the amount of available dynamic slack for different checkpoint overhead (i.e.,  $\gamma = 0.01, 0.05$  and  $0.10$ ).

section may not be enough to compensate the reliability loss due to energy management. In the next Section, we consider to exploit multiple recovery sections to enhance reliability, especially for the case of more slack being available (e.g.,  $S > c_k$ ).

#### 4.2 Checkpoints with Multiple Recovery Sections

Suppose that  $b$  ( $\geq 1$ ) recovery sections are needed/scheduled to preserve system reliability. Equation 10 can be generalized as:

$$S \geq n \cdot r + b \cdot \left(r + \frac{c_k}{n}\right) = \left((n+b)\gamma + \frac{b}{n}\right) c_k \quad (13)$$

With the optimal number of checkpoints  $n_{b,opt}$  (i.e.,  $\lfloor \sqrt{\frac{b}{\gamma}} \rfloor$  or  $\lceil \sqrt{\frac{b}{\gamma}} \rceil$ ), the minimum amount of slack needed due to timing constraints can be found as  $S_{b,min}^{time} = (b \cdot \gamma + 2\sqrt{b \cdot \gamma})c_k$ . When more slack is available, the remaining slack  $S - n_{b,opt} \cdot r - b\left(r + \frac{c_k}{n_{b,opt}}\right)$  (if any) can be used by energy management schemes to scale down the execution of the primary sections for energy savings. The reduced frequency to execute the primary sections will be

$$f_{b,ckpt} = \frac{c_k + n_{b,opt} \cdot r}{c_k + S - b\left(r + \frac{c_k}{n_{b,opt}}\right)} \quad (14)$$

4.2.1 *Reliability for Multiple Recovery Sections.* From Equation 14, each primary section will take  $t_{b,primary} = \frac{c_k + S - b(r + \frac{c_k}{n_{opt}})}{n_{opt}}$  time units. Considering that the fault rate at frequency  $f_{b,ckpt}$  is  $\lambda(f_{b,ckpt}) = \lambda_0 10^{\frac{d(1-f_{b,ckpt})}{1-f_{min}}}$  (see Section 2), the probability of having fault(s) during the execution of one primary section is  $\rho_{b,primary} = 1 - e^{-\lambda(f_{b,ckpt})t_{b,primary}}$ . Notice that, the recovery sections are executed at  $f_{max}$  and the probability of having fault(s) during the execution of one recovery section is  $\rho_{b,recovery} = 1 - e^{-\lambda_0(r + \frac{c_k}{n_{b,opt}})}$ .

With  $b$  recovery sections, the reliability  $R_k(b)$  of task  $T_k$  will be the summation of the probability of *all* primary sections being executed correctly and the probability of having *any*  $x$  ( $x = 1, \dots, b$ ) faulty primary sections while there are  $x$  recovery sections being executed correctly. Notice that, the recovery sections are activated *one at a time* when they are needed. For example, to recover  $x$  faulty primary sections, if there is no faults during the execution of the first  $x$  recovery sections, it is not necessary to invoke the remaining recovery sections. Otherwise, the next recovery section is activated and so on, until there are  $x$  recovery sections are correctly executed. Therefore, we have

$$R_k(b) = \sum_{x=0}^b \left[ \binom{n_{b,opt}}{x} \cdot (1 - \rho_{b,primary})^{n_{b,opt}-x} \cdot \rho_{b,primary}^x \cdot Pr(b, x, \rho_{b,recovery}) \right] \quad (15)$$

where  $\binom{n_{b,opt}}{x}$  is the number of combinations of having  $x$  faulty sections in the  $n_{b,opt}$  primary sections.  $Pr(b, x, \rho_{b,recovery})$  is the probability of  $x$  faulty primary sections being successfully recovered by the  $b$  recovery sections. Notice that, when  $x = 0$ , no faulty primary section needs to be recovered and there is  $Pr(b, 0, \rho_{b,recovery}) = 1$ . Therefore, we have

$$Pr(b, x, \rho_{b,recovery}) = \begin{cases} 1 & x = 0 \\ (1 - \rho_{b,recovery})^{x-1} (1 - \rho_{b,recovery}^{b-x+1}) & x \geq 1 \end{cases} \quad (16)$$

From Equations 14, 15 and 16, clearly it is not practical to seek the close formula for the minimum number of recovery sections needed to ensure  $R_k(b) \geq R_k^0$ . In what follows, we show some analysis results regarding the number of recovery sections employed and the reliability achieved versus the amount of available slack.

Notice that, the reduced frequency  $f_{ckpt}$  is limited by the energy efficient frequency  $f_{ee}$ . From Equation 14, we can find that the maximum amount of slack can be used to processing  $T_k$  to be

$$US_{b,ckpt}^{max} = \left( \frac{1 + n_{b,opt} \cdot \gamma}{f_{ee}} + b \left( \gamma + \frac{1}{n_{b,opt}} \right) - 1 \right) c_k \quad (17)$$

Figure 5 shows the normalized probability of failure,  $\frac{1-R_k^{ckpt}}{1-R_k^0}$ , for different numbers of recovery sections. Here, the same parameters as in last Section are used and the checkpoint overhead is assumed to be  $\gamma = 0.05$ . From the figures, we can see that, as the number of recovery sections increases, the minimum amount of slack needed increases, which is close to  $c_k$  when three recovery sections (i.e.,  $b = 3$ ) are scheduled (Figure 5b). Moreover, as the amount of slack increases, more slack is available for energy management which leads to lower processing frequencies, higher fault rates and thus lower levels of reliability achieved, which is the same

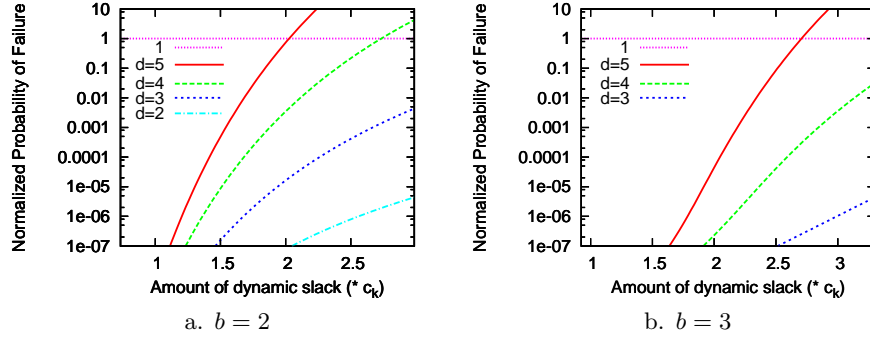


Fig. 5. The normalized probability of failure vs. the amount of available dynamic slack.

observation as in Section 4.1.

For the case of low fault rate increase (e.g.,  $d \leq 2$ ), when there are three recovery sections (Figure 5b), the normalized probability of failure is less than  $10^{-7}$  and is not shown in the figures, which is the same for  $d = 0$  and  $b = 2$  in Figure 5a. When the fault rate increase is high (e.g.,  $d = 5$ ), even three recovery sections cannot guarantee  $R_k^0$  (i.e., the normalized probability of failure is larger than 1). However, as shown in next Section, for the cases where  $R_k^0$  is preserved, compared with the RA-Greedy scheme, checkpointing will result in smaller recovery sections, and more energy savings may be expected.

**4.2.2 Expected Energy Consumption with Checkpoints.** With reduced frequency  $f_{b,ckpt}$  (see Equation 14), the energy consumption for executing one primary section is  $E_{primary} = \left(\beta + \left(\frac{f_{b,ckpt}}{f_{max}}\right)^m\right) P_d^{max} \cdot t_{b,primary}$ . Recall that recovery sections are executed (if needed) at the maximum frequency  $f_{max}$ . The energy consumption for executing one recovery section will be  $E_{recovery} = \left(\gamma + \frac{1}{n_{b,opt}}\right) E_k^0$ , where  $E_k^0$  is the energy consumption to execute task  $T_k$  for time  $c_k$  at  $f_{max}$ .

Notice that, for the  $q^{th}$  recovery section ( $q = 1, \dots, b$ ), it will *not* be invoked if the number of faulty primary sections  $x$  is less than  $q$  (i.e.,  $0 \leq x < q$ ) and the first  $(q - 1)$  recovery sections successfully recover all the  $x$  faulty primary sections. From previous discussion, when there are  $x$  ( $0 \leq x < q$ ) faulty primary sections, the probability of these faulty primary sections being successfully recovered by the first  $(q - 1)$  recovery sections can be given by  $Pr(q - 1, x, \rho_{b,recovery})$ . Therefore, considering the probability of each recovery section being executed, the expected energy consumption for executing task  $T_k$  will be

$$E_k^{b,ckpt} = n_{opt} \cdot E_{primary} + \sum_{q=1}^b (Pr_q \cdot E_{recovery}) \quad (18)$$

where the first part is always consumed and is the energy for executing the primary sections (including the checkpoints), and the second part is the expected energy consumption for executing the recovery sections.  $Pr_q$  is the probability of the  $q^{th}$



recovery section being invoked, which is given as

$$Pr_q = 1 - \sum_{x=0}^{q-1} \left[ \binom{n_{b,opt}}{x} (1 - \rho_{b,primary})^{n_{b,opt}-x} \cdot \rho_{b,primary}^x \cdot Pr(q-1, x, \rho_{b,recovery}) \right] \quad (19)$$

Due to the overhead of checkpoints, in order to obtain energy savings (i.e.,  $E_k^{ckpt} < E_k^0$ ), there is a minimum amount of dynamic slack  $S_{min}^{energy}$  needed for energy management. Again, due to the complexity of Equation 18, it is hard to get the close formula for  $S_{min}^{energy}$  and we illustrate the relation between  $S_{min}^{energy}$  and checkpoint overhead  $\gamma$  in the following analysis.

Corresponding to the reliability analysis with one recovery section in Section 4.1, Figure 6abc show the normalized expected energy consumption,  $\frac{E_k^{1,ckpt}}{E_k^0}$ , for different checkpoint overheads with the amount of slack being limited by  $c_k$ . For different fault rate changes (i.e., different values of  $d$ ), due to the low probability of recovery section being executed (lower than  $10^{-5}$  even when  $d = 5$ ), the expected energy consumption is almost the same for a given checkpoint overhead and amount of available dynamic slack. Therefore, we only show the normalized expected energy consumption for the worst case of  $d = 5$ .

From the figures, we can see that, although it is feasible to employ checkpoints when the amount of dynamic slack is larger than  $S_{min}^{time}$ , due to the energy overhead of checkpoints, no energy savings could be obtained until the amount of slack is more than  $S_{min}^{energy}$ . The smaller the checkpoint overhead, the lower the value of  $S_{min}^{energy}$  and the more energy savings could be obtained for a given amount of dynamic slack. When the checkpoint overhead is large (e.g.,  $\gamma = 0.1$ , Figure 6c), almost no energy savings could be obtained for the case considered.

Figure 6def further show the normalized energy consumption for multiple recovery sections considering the extended range of available slack. For comparison, the normalized energy consumption for the RA-Greedy scheme is also shown in the figure. Notice that, the ranges of the amount of slack could be exploited are different for different numbers of recovery sections being employed. From the figure, we can see that, when more than one recovery sections are employed, checkpointing with recoveries consume more energy than the RA-Greedy scheme, except for the case where overhead is small (e.g.,  $\gamma = 0.01$  in Figure 6d). When checkpoint overhead is relatively large (e.g.,  $\gamma \geq 0.05$ ), checkpointing scheme should not be exploited when the RA-Greedy scheme is applicable (i.e., when  $S > c_k$ ).

Considering both reliability (Section 4.2.1) and energy savings (Section 4.2.2), checkpointing should *not* be employed when the checkpoint overhead is relatively large (e.g.,  $\gamma \geq 0.05$ ). No more than one recovery section may be employed even when checkpoint overhead is relatively small (e.g.,  $\gamma = 0.01$ ). Moreover, although more energy savings could be obtained by checkpointing compared with the RA-Greedy scheme, limitation may exist on the amount of employed slack due to reliability consideration, especially for the case where the fault rate increases dramatically with reduced frequencies and supply voltages (e.g.,  $d = 5$ ).

We have analyzed the performance of the reliability-aware energy management schemes for a single task. In what follows, to illustrate the merits of our proposed schemes and see how they perform for overall system reliability and energy savings,

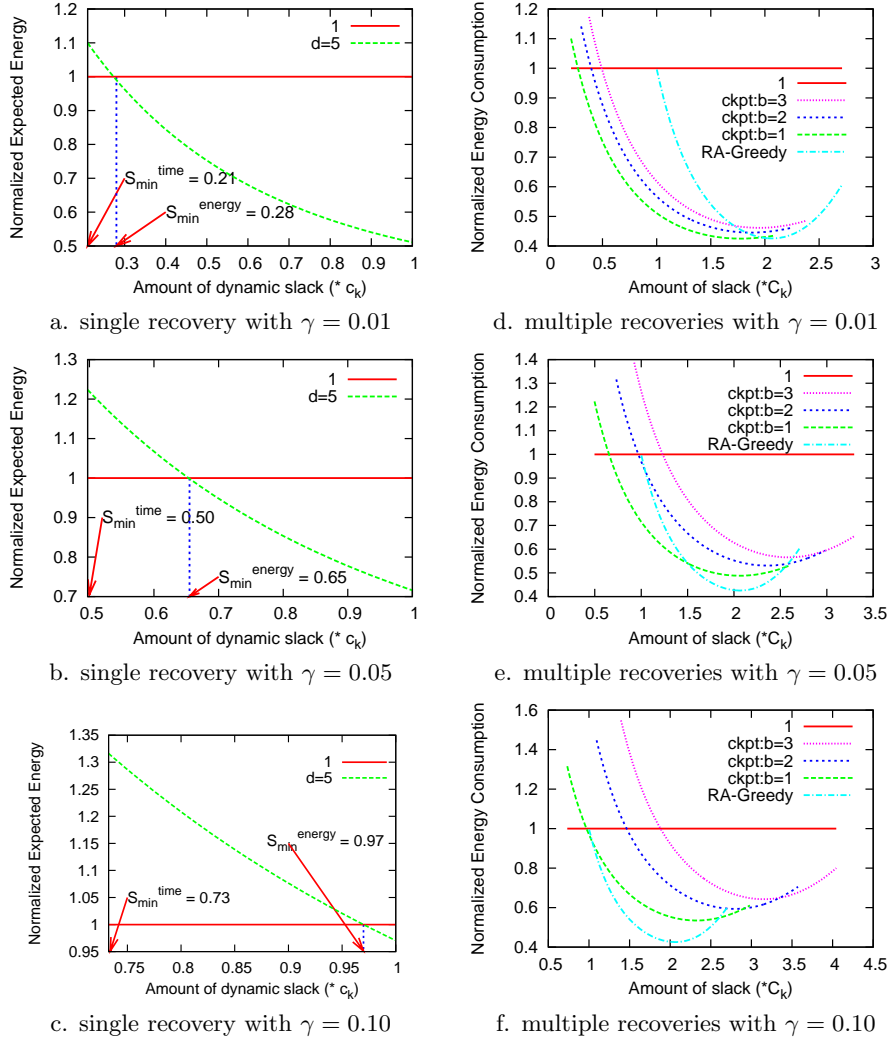


Fig. 6. The normalized expected energy consumption under different amount of available dynamic slack.

we present simulation results for dependable real-time applications that consist of a set of aperiodic tasks. We compare the energy savings as well as system reliability of the new proposed schemes with ordinary energy management schemes.

## 5. SIMULATION RESULTS AND DISCUSSION

In the simulations, we consider four different schemes: a) *no power management (NPM)*, which is used as the baseline for comparison; b) *ordinary greedy power management (Greedy)*, which allocates all available dynamic slack for next ready task to save energy without considering system reliability; c) *reliability-aware greedy*

*power management (RA-Greedy)*, which dynamically allocates a recovery for the next ready task before applying greedy power management. When the amount of available dynamic slack is less than the size of next ready task, the slack is not used and saved for future tasks; d) *reliability-aware power management with checkpoints (Ckpt)*, which is the same as RA-Greedy except that checkpoints are employed when the amount of available dynamic slack is less than the size of next ready task. As discussed in last Section, only one recovery section is considered in the simulations.

For the system parameters, as discussed in Section 2, we use normalized frequency with  $f_{max} = 1$  and assume frequency can be changed continuously. Moreover, corresponding to the analysis in Section 3 and 4, we assume  $\alpha = 0$ ,  $\beta = 0.1$  and  $m = 3$ . That is, we assume the working system is always on and focus on system active power. For the effects of different values of  $\alpha$  and  $\beta$  on energy management, see [Zhu et al. 2004; Zhu et al. 2005] for more discussions. The same as in Section 3, we assume that faults follow a Poisson distribution with an average fault rate as  $\lambda_0 = 10^{-6}$  at  $f_{max}$  (and corresponding  $V_{max}$ ). We vary the values of  $d$  (as 0, 2 and 5 respectively) for different changes in fault rates due to the effects of frequency and voltage scaling [Ernst et al. 2004]. An application fails if *any* task in the application fails and there is no recovery *or* both the task and its recovery fail.

The number of tasks in an application is randomly generated between 5 and 20, where the WCETs of tasks are uniformly distributed in the range of 1 and 10. When every task in an application uses its WCET, we assume that the application finishes just in time and the system reliability is satisfactory. To emulate the runtime behaviors of tasks, a parameter  $\sigma$  is used as an application-wide average over worst execution time, which also indicates the amount of dynamic slack available on average during execution. Smaller values of  $\sigma$  imply more dynamic slack. The value of  $\sigma_i$  for task  $T_i$  in the application is generated from a uniform distribution with an average value of  $\sigma$ . The actual execution time of  $T_i$  follows a similar uniform distribution with an average value of  $\sigma_i \cdot c_i$ , where  $c_i$  is the WCET of task  $T_i$ . For each result point in the graphs, 100 task sets are generated and each task set is executed 100,000 times, and the result is the average of all the runs.

### 5.1 Performance of RA-Greedy

First, we compare the performance of *Greedy* and *RA-Greedy* on reliability and energy consumption. For different fault rate increases, Figure 7abc show the probability of failure when executing the applications with different average system loads (i.e., different amounts of dynamic slack).

Notice that, *NPM* executes every task at the maximum frequency  $f_{max}$  and the fault rate is always  $\lambda_0 = 10^{-6}$ . From the figures, we can see that for a given average system load, the probability of failure under *NPM* is roughly the same, which is not affected by the different fault rate changes (i.e., different values of  $d$ ). When the average system load increases, the applications run longer and the probability of failure under *NPM* increases linearly. Note the log scale of Y-axis in Figure 7abc.

From the figure, it can be seen that the *Greedy* scheme results in higher probability of failure than *NPM* even when  $d = 0$  (i.e., constant fault rate), which comes from the extended execution of tasks due to energy management. When fault rate increases with reduced frequencies and supply voltages (i.e.,  $d > 0$ ), the probability of failure under *Greedy* scheme increases exponentially as  $d$  increases. For example,

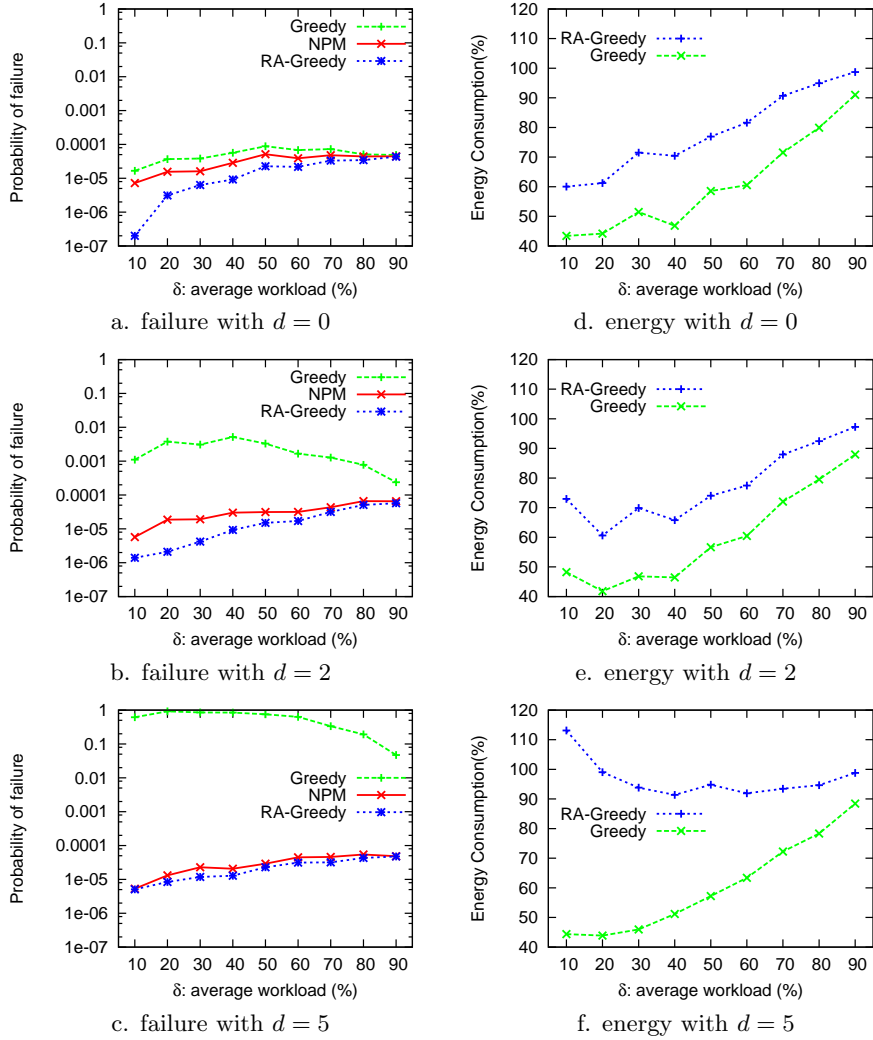


Fig. 7. The probability of failure and normalized expected energy consumption under different average system loads.

when  $d = 5$ , *Greedy* scheme almost always leads to system failure (with probability of failure close to 1), especially for the case of low average system loads where more dynamic slack exists. When the average system load increases, the probability of failure under *Greedy* scheme increases first and then decreases, the reason is because of the limitation of  $f_{ee} = 0.37$ . When the average system load is extremely low (e.g.,  $\sigma < 20\%$ ), tasks in an application always run at  $f_{ee}$  and the probability of failure mainly depends on the execution time, which increases as average system load increases. However, as average system load continues to increase, less slack is available and tasks need to run at higher frequencies than  $f_{ee}$ , which has lower

fault rates and thus leads to lower probability of failure. Moreover, from the figures, we can also see that *RA-Greedy* scheme always has a lower probability of failure (i.e., higher system reliability) than *NPM* regardless the fault rate changes, which coincides with the analysis in Section 3.2.1.

Figure 7def further show the corresponding normalized energy consumption for *Greedy* and *RA-Greedy* schemes with the one consumed by *NPM* as a baseline. As *Greedy* scheme does not consider system reliability when reclaiming dynamic slack for energy savings, the normalized energy consumption for *Greedy* scheme only depends on the average system load and is roughly the same for different fault rate changes. For *RA-Greedy* scheme, by providing an additional recovery for maintaining system reliability, it consumes from 10% to 20% more energy than *Greedy* scheme when the fault rate only increases moderately with reduced frequencies and supply voltages (i.e.,  $d \leq 2$ ). However, when the fault rate increases dramatically (e.g.,  $d = 5$ ), the probability of failure for the primary scaled-down execution is close to 1 when the average system load is low (see Figure 7c) and the recovery task is almost always executed, which leads to higher energy consumption than *NPM* (Figure 7f). Therefore, when the fault rate increases dramatically with reduced frequencies and supply voltages, it will be more energy efficient to use less dynamic slack for energy management to keep the fault rate at a reasonable level.

## 5.2 Effects of Checkpoints

Considering the checkpoint overhead could be very small [Quaglia and Santoro 2003], we use  $r = 0.01, 0.05, 0.1$ , which corresponds to *Ckpt-0.01*, *Ckpt-0.05* and *Ckpt-0.10* in the following figures, respectively. Recall that the size of tasks is in the range of  $[1, 10]$  inclusively, which leads to the average  $\gamma = 0.002, 0.01$  and  $0.02$ , smaller than the ones we used in the analysis in Section 4.

Figure 8abc show the probability of failure for the schemes of *RA-Greedy* and *Ckpt* with different checkpoint overheads. From the figure, when the fault rate increase is moderate (i.e.,  $d \leq 2$ ), *Ckpt* achieves slightly better system reliability (lower probability of failure) by providing an additional recovery when the amount of available dynamic slack is less than the size of the next ready task. When the checkpoint overhead is smaller, *Ckpt* has more chances to use the dynamic slack and generally gets better system reliability. However, when the fault rate increase is high (e.g.,  $d = 5$ ), the additional recovery is almost always executed and overall probability of failure increases due to the execution overhead of checkpoints. Smaller checkpoint overhead leads to higher probability of using checkpoints and thus results in higher probability of failure.

Figure 8def further show the corresponding normalized energy consumption for *RA-Greedy* and *Ckpt* with different checkpoint overheads. With additional chances for energy management, *Ckpt* with smaller checkpoint overhead consumes less energy, and all of them is less than the one consumed by *RA-Greedy*. The same reason as before, due to the limitation of  $f_{ee}$  and higher failure rates, the normalized energy consumption decreases first and then increases as the average system load increases. All schemes consumes more energy than *NPM* when  $d = 5$  and  $\sigma \leq 10\%$ .

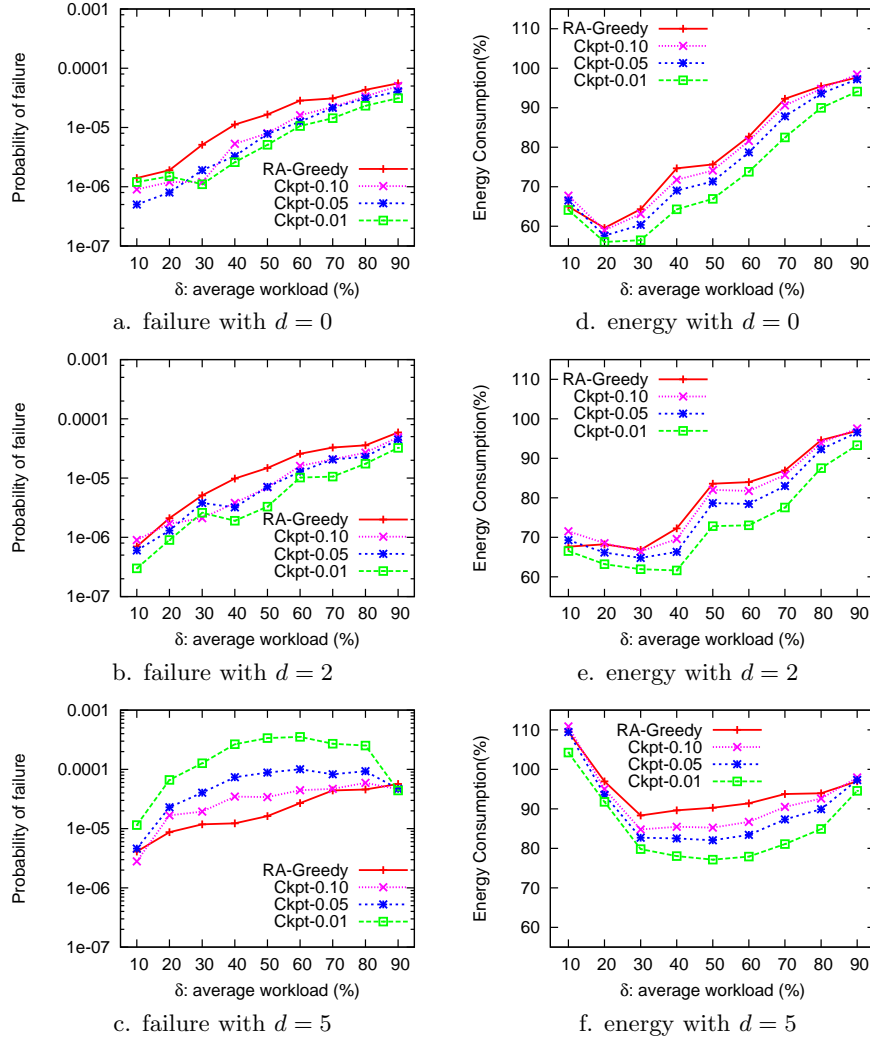


Fig. 8. The probability of failure and normalized expected energy consumption with checkpoints.

## 6. CLOSELY RELATED WORK

Using the primary/backup recovery model, Unsal *et al.* proposed to postpone the execution of backup tasks to minimize the overlap of primary and backup execution and thus the energy consumption [Unsal *et al.* 2002]. The optimal number of checkpoints, evenly or unevenly distributed, to achieve minimal energy consumption while tolerating one transient fault was explored by Melhem *et al.* in [Melhem *et al.* 2004]. Elnozahy *et al.* proposed an *Optimistic TMR (OTMR)* scheme that reduces the energy consumption for traditional TMR systems by allowing one processing unit to slow down provided that it can catch up and finish the computation before

the application deadline [Elnozahy et al. 2002]. The optimal frequency settings for OTMR was further explored in [Zhu et al. 2004]. Assuming a Poisson fault model, Zhang *et al.* proposed an adaptive checkpointing scheme that dynamically adjusts checkpoint intervals for energy savings while tolerating a fixed number of faults for a single task [Zhang and Chakrabarty 2003]. The work is further extended to a set of periodic tasks [Zhang et al. 2003], and moreover, faults within checkpoints are also considered [Zhang and Chakrabarty 2004].

Most of the previous research either focused on tolerating fixed number of faults [Elnozahy et al. 2002; Melhem et al. 2004] or assumed constant fault rate [Zhang and Chakrabarty 2003; 2004; Zhu et al. 2004] when applying frequency and voltage scaling for energy savings. The relation between fault rate and voltage scaling was explored and hardware error detection and correction schemes have been proposed [Ernst et al. 2004]. An exponential fault rate model with voltage scaling is proposed in [Zhu et al. 2004] and the combination of information (in hardware) and temporal redundancy is explored for preserving reliability and energy savings [Ejlali et al. 2005]. The work reported in this paper is different from all previous work in that we address the system reliability problem when exploring dynamic slack for energy savings, while explicitly taking the effects of energy management on fault rates into consideration.

## 7. CONCLUSIONS

As fault rates generally increase with reduced supply voltages, energy management exploring slack time through voltage scaling will reduce system reliability, which is undesirable, especially for mission critical applications (e.g., satellite and surveillance systems), where system reliability is as important as (or even more important than) energy consumption. Considering the effects of voltage scaling on fault rates, we propose *reliability-aware* dynamic energy management schemes that preserve system reliability while exploring dynamic slack for energy savings.

By scheduling an additional recovery task before reclaiming dynamic slack for energy management, the proposed reliability-aware energy management scheme ensures that the system reliability achieved is higher than the case when there is no power management. Checkpointing techniques are further explored to more efficiently use the dynamic slack especially for the case where the slack is not enough to schedule a recovery for a whole task. The performance of the proposed schemes is analyzed and evaluated through simulations for both system reliability and energy savings. The results show that, the proposed schemes can achieve comparable energy savings as ordinary energy management schemes while preserving system reliability. For checkpointing techniques, no more than one recovery section may be exploited for energy efficiency, especially when the checkpoint overhead is large. The ordinary energy management schemes that ignore the effects of energy management on fault rates are too optimistic and could lead to drastically decreased system reliability.

## ACKNOWLEDGMENTS

The author would like to thank Prof. Rami Melhem and Prof. Daniel Mossé for their inspiring discussions and suggestions in the early stages of this work. Also,

the author would like to thank the anonymous reviewers whose comments helped to improve the paper. Moreover, the author would like to thank Dr. Hakan Aydin for his insightful discussions when revising the paper.

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Received January 2006; accepted May 2006